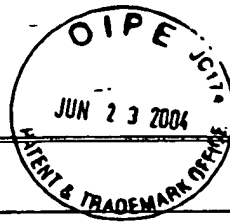


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. <b>NEW APPLICATION</b> 62/657,121			
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT NATSUKO NOBUKUNI, ET AL.		FILED HEREWITH		GROUP 2655	
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE			
AA	5,732,062	03/24/98	Yokoi, et al.						
AB	5,848,043	12/08/98	Takada, et al.						
AC	5,530,688	06/1996	Hurst, Jr., et al.						
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AH									
AI									
AJ									
AK									
AL									
AM									
AN									
FOREIGN PATENT DOCUMENTS									
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO					
AO	62-259229	11/11/87	Japan			X			
AP	63-266632	11/02/88	Japan			X			
AQ	63-22439	01/29/88	Japan			X			
AR	7-37252	02/07/95	Japan			X			
AS	9-7176	01/10/97	Japan			X			
AT	8-287465	11/01/96	Japan			X			
AU	9-282661	10/31/97	Japan			X			
AV	7-37251	02/07/95	Japan			X			
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
AW	N. Nobukuni, et al. J. Appl Physics, "Microstructural changes in GeSbTe film during repetitious overwriting in phase-change optical recording," December 15, 1995, pages 6980-6988.								
AX									
AY									
AZ									
Examiner	Muhammad Edun Primary Examiner			Date Considered 10/12/04					

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 238397US-2 DIV		APPLN. SERIAL NO. <b>NEW APPLICATION</b> 10/677,121	
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				GROUP 2655			
<b>U.S. PATENT DOCUMENTS</b>							
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	AB						
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	AK						
	AL						
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	AN						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	0 887 888	09/30/98	Europe (English)			
	AP	0 902 424	03/17/99	Europe (English)			
	AQ	0 388 897	09/26/90	Europe (English)			
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ						
Examiner		Muhammad Edun Primary Examiner			Date Considered 10/17/04		

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
238397US2DIVSERIAL NO.  
10/657,121

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Natsuko NOBUKUNI, et al.

FILING DATE

September 9, 2003

GROUP

2655

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	AC						
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	AM						
	AN						

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>HE</i>	AO	0 847 049	06/10/1998	EUROPE		
<i>HE</i>	AP	0 217 293	04/08/1987	EUROPE		
<i>HE</i>	AQ	0 834 874	04/08/1998	EUROPE		
<i>HE</i>	AR	1 047 058	10/25/2000	EUROPE		
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	AU					
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>HE</i>	AW	M. HORIE, et al., Optical Data Storage, Proceedings of SPIE, vol. 4342, XP-002267102, pages 76-87, "MATERIAL CHARACTERIZATION AND APPLICATION OF EUTECTIC SbTe BASED PHASE-CHANGE OPTICAL RECORDING MEDIA", April, 2001
<i>HE</i>	AX	Patent Abstracts of Japan, JP 10-241160, September 11, 1998
<i>HE</i>	AY	Patent Abstracts of Japan, JP 61-020236, January 29, 1986
	AZ	

☐ Additional References sheet(s) attached

Examiner

Muhammad Edun  
Primary Examiner

Date Considered

10/17/04

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



**LIST OF RELATED CASES**

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
238397US2 DIV*	10/657,121	09/09/03	NOBUKUNI et al.
250703US2 RE	10/825,439	04/16/04	NOBUKUNI et al.

Muhammad Edun  
Primary Examiner

10/17/04

\*Present Application; listed for information

GJM/sba

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